Excellent Integrated System Limited

Stocking Distributor

Click to view price, real time Inventory, Delivery & Lifecycle Information:

ON Semiconductor BUL642D2G

For any questions, you can email us directly: sales@integrated-circuit.com



High Speed, High Gain Bipolar NPN Transistor with Integrated Collector-Emitter and Built-in Efficient Antisaturation Network

The BUL642D2 is a state-of-the-art High Speed High Gain Bipolar Transistor (H2BIP). Tight dynamic characteristics and lot to lot minimum spread (150 ns on storage time) make it ideally suitable for Light Ballast Application. A new development process brings avalanche energy capability, making the device extremely rugged.

Features

- Low Base Drive Requirement
- High Peak DC Current Gain (55 Typical) @ $I_C = 300 \text{ mA/5 V}$
- Extremely Low Storage Time Min/Max Guarantees Due to the H2BIP Structure which Minimizes the Spread
- Integrated Collector-Emitter Free Wheeling Diode
- Fully Characterized Dynamic V_{CEsat}
- "Six Sigma" Process Providing Tight and Reproducible Parameter Spreads
- Avalanche Energy 20 mJ Typical Capability
- Pb-Free Package is Available*



ON Semiconductor®

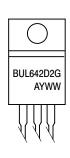
http://onsemi.com

3 AMPERES 825 VOLTS 75 WATTS POWER TRANSISTOR



MARKING DIAGRAM





BUL642D2 = Device Code

A = Assembly Location

Y = Year

WW = Work Week

G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping
BUL642D2	TO-220	50 Units/Rail
BUL642D2G	TO-220 (Pb-Free)	50 Units/Rail

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.



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Datasheet of BUL642D2G - TRANS NPN 440V 3A TO-220AB

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MAXIMUM RATINGS

	Rating		Symbol	Value	Unit
Collector-Emitter S	Collector–Emitter Sustaining Voltage		V_{CEO}	440	Vdc
Collector-Base Bro	eakdown Voltage		V _{CES}	825	Vdc
Emitter-Base Volta	ge		V _{EBO}	11	Vdc
Collector Current	ContinuousPeak (Note 1)		I _C I _{CM}	3.0 8.0	Adc
Base Current	- Continuous - Peak (Note 1)		I _B I _{BM}	2.0 4.0	Adc
*Total Device Dissi	pation @ T _C = 25°C *Derate above 25°C		P _D	75 0.6	W W/°C
Operating and Sto	age Temperature		T _J , T _{stq}	-65 to +150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

TYPICAL GAIN

Rating		Value	Unit
Typical Gain @ $I_C = 1$ A, $V_{CE} = 2$ V Typical A, $V_{CE} = 1$ V	h _{FE} h _{FE}	45 50	<u> </u>

THERMAL CHARACTERISTICS

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.6	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	°C/W
Maximum Lead Temperature for Soldering Purposes: 1/8 in. from Case for 5 seconds	TL	260	°C

^{1.} Pulse Test: Pulse Width = 5.0 ms, Duty Cycle = 10%

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ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Characteristic				Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTI	cs					•	•	
Collector–Emitter Sustaining Voltage $(I_{C} = 200 \text{ mA}, L = 25 \text{ mH})$				V _{CEO(sus)}	440	_	_	Vdc
Collector-Base Breakd	own Voltage		(I _{CBO} = 1 mA)	V_{CBO}	825	-	-	Vdc
Emitter-Base Breakdov	wn Voltage		$(I_{EBO} = 1 \text{ mA})$	V _{EBO}	11	-	-	Vdc
Collector Cutoff Current	t (V _{CE} = Rat	$red V_{CEO}, I_B = 0)$	@ T _C = 25°C @ T _C = 125°C	I _{CEO}	- -	_ _	200 1000	μAdc
Collector Cutoff Current	t (V _{CE} = Rated	$dV_{CES}, V_{EB} = 0$	@ T _C = 25°C @ T _C = 125°C	I _{CES}	<u> </u>	_ _	100 1000	μAdc
Emitter-Cutoff Current		(V _{EE}	$I_{c} = 10 \text{ Vdc}, I_{C} = 0$	I _{EBO}	-	-	100	μAdc
ON CHARACTERISTIC	s					•	•	
Base–Emitter Saturation Voltage $(IC = 0.5 \text{ Adc}, I_B = 100 \text{ mAdc} \\ (I_C = 1 \text{ Adc}, I_B = 0.2 \text{ Adc})$				V _{BE(sat)}	- -	- -	1.1 1.5	Vdc
Collector–Emitter Saturation Voltage $ (I_{C} = 0.5 \text{ Adc, } I_{B} = 50 \text{ mA} \\ (I_{C} = 2 \text{ Adc, } I_{B} = 0.2 \text{ Adc, } I_{C} = 0.5 \text{ Adc, } I_{C}$			dc, I _B = 50 mAdc) Adc, I _B = 0.2 Adc)	V _{CE(sat)}	- -	- -	0.5 1.5	Vdc
DC Current Gain			Adc, $V_{CE} = 1 \text{ Vdc}$) Adc, $V_{CE} = 3 \text{ Vdc}$)	h _{FE}	16 18	- -	- -	-
DYNAMIC SATURATIO	N VOLTAGE							
Dynamic Saturation	$I_{C} = 0.5 \text{ Adc}$ $I_{B1} = 50 \text{ mAdc}$ $V_{CC} = 125 \text{ Vdc}$ $I_{C} = 1 \text{ Adc}$ $I_{B1} = 100 \text{ mAdc}$ $V_{CC} = 300 \text{ Vdc}$	@ 1 μs	@ T _C = 25°C @ T _C = 125°C	V _{CE(dsat)}	<u>-</u>	2.0 5.0	_ _	V
		@ 3 μs	@ T _C = 25°C		- -	0.2 1.3	_ _	
		@ 1 μs	@ T _C = 25°C @ T _C = 125°C		- -	4.5 10	_ _	
		@ 3 μs	@ T _C = 25°C		-	1.0 3.0	_ _	
OYNAMIC CHARACTER	RISTICS							
Current Gain Bandwidth	n I _C = 0.5 Adc, V _C	_E = 10 Vdc, f = 1 f	ИНz	f _T	-	13	_	MHz
Output Capacitance @ V _{cb} = 10 V, I _E = 0, f = 1 MHz				C_{ob}	-	70	150	pF
Input Capacitance @ V _{EB} = 8 V, f = 1 MHz			C _{ib}	-	500	1000	pF	
DIODE CHARACTERIS	STICS							
Forward Diode Voltage (I _{EC} (I _{EC}			$(I_{EC} = 0.5 \text{ Adc})$ $(I_{EC} = 1.0 \text{ Adc})$	V _{EC}	-	0.8 1.0	1.5 2.0	V
SWITCHING CHARAC	TERISTICS: Res	istive Load (D.C.	≤ 10%, Pulse Widtl	n = 70 μs)				
Delay Time $I_C = 0.5 \text{ Adc}$			t _d	-	60	400	ns	
Rise Time			I _{B1} = 45 mA	t _r	_	160	1100	ns
Storage Time I _{B2} =			$I_{B2} = 500 \text{ mA}$	t _s	_	0.5	1400	μs
Fall Time V _{CC} = 125				t _f	_	0.4	600	ns

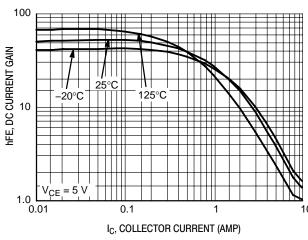


Figure 1. DC Current Gain

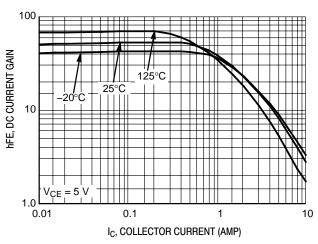


Figure 2. DC Current Gain

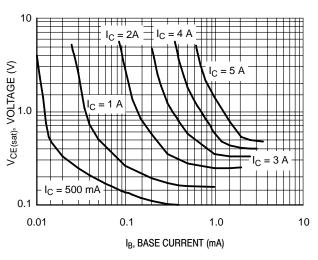


Figure 3. Collector Saturation Region

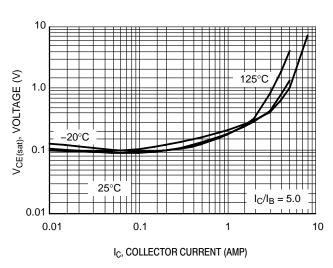


Figure 4. Collector-Emitter Saturation Voltage

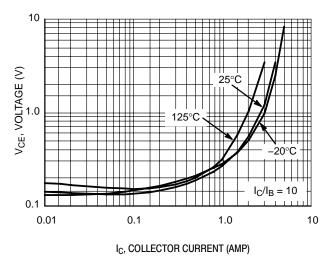


Figure 5. Collector-Emitter Saturation Voltage

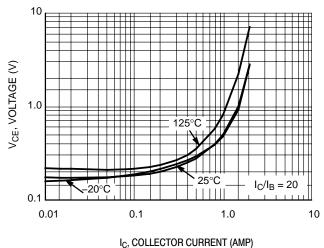


Figure 6. Collector-Emitter Saturation Voltage

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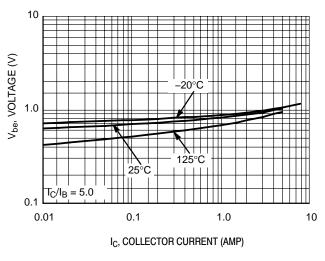
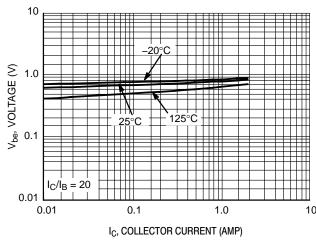


Figure 7. Base-Emitter Saturation Voltage

Figure 8. Base-Emitter Saturation Voltage



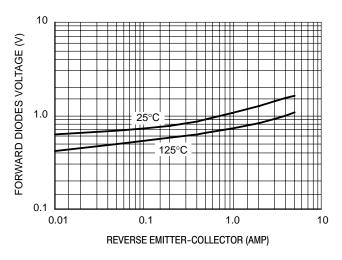
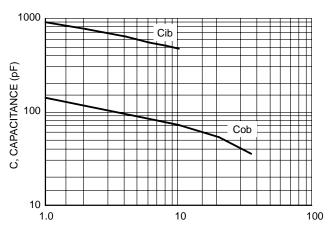
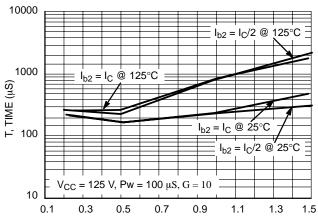


Figure 9. Base-Emitter Saturation Voltage

Figure 10. Forward Diode Voltage





V_r, REVERSE VOLTAGE (V)

Figure 11. Capacitance

Figure 12. Resistive Switch Time, Storage Time T_{ON}

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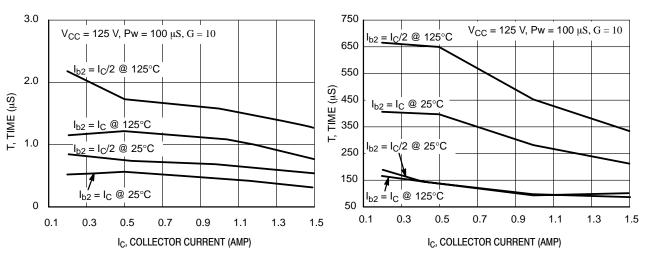


Figure 13. Resistive Switch Time, Storage Time

Figure 14. Resistive Switch Time, Fall Time

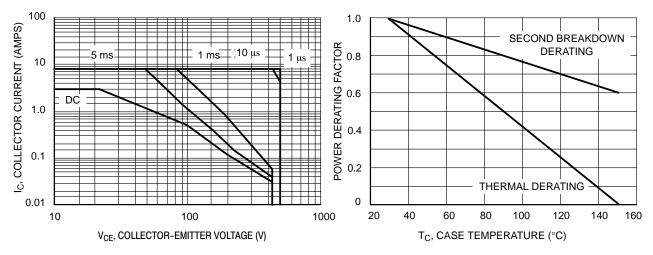


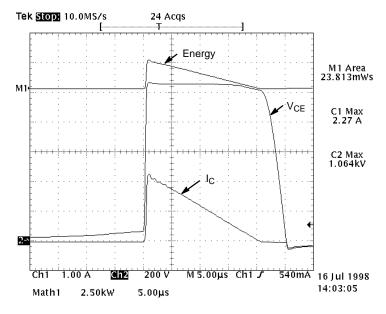
Figure 15.

Figure 16. Power Derating

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate I_C – V_{CE} limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate. The data of Figure 15 is based on T_C = 25°C; $T_{j(pk)}$ is variable depending on power level. Second breakdown pulse limits do not derate like

thermal limitations. Allowable current at the voltages shown on Figure 10 may be found at any case temperature by using the appropriate curve on Figure 16.

 $T_{j(pk)}$ may be calculated from the data in Figure 18. At any case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.



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Figure 17. Typical Avalanche Energy Test/Waveforms

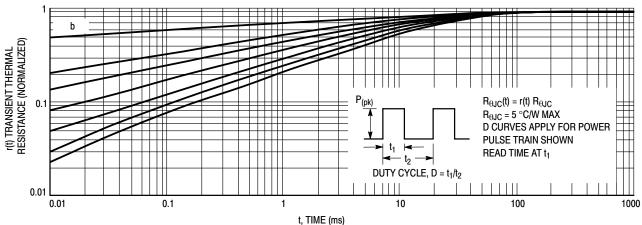


Figure 18. Thermal Response



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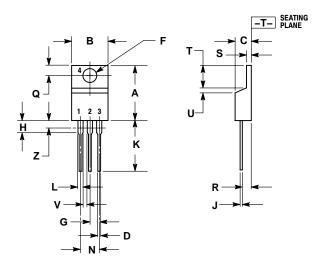
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PACKAGE DIMENSIONS

TO-220 CASE 221A-09 **ISSUE AA**



NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

	INC	HES	MILLIMETERS						
DIM	MIN	MAX	MIN	MAX					
Α	0.570	0.620	14.48	15.75					
В	0.380	0.405	9.66	10.28					
С	0.160	0.190	4.07	4.82					
D	0.025	0.035	0.64	0.88					
F	0.142	0.147	3.61	3.73					
G	0.095	0.105	2.42	2.66					
Н	0.110	0.155	2.80	3.93					
J	0.018	0.025	0.46	0.64					
K	0.500	0.562	12.70	14.27					
L	0.045	0.060	1.15	1.52					
N	0.190	0.210	4.83	5.33					
Q	0.100	0.120 2.54	0.120 2.54	2.54	2.54	2.54	0 2.54	0.120 2.54 3	3.04
R	0.080	0.110	2.04	2.79					
S	0.045	0.055	1.15	1.39					
Т	0.235	0.255	5.97	6.47					
U	0.000	0.050	0.00	1.27					
٧	0.045		1.15						
Z	0.080			2.04					

STYLE 1:

PIN 1. BASE

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